R4 🛛 9

10

TE

12 🛛 E4

11 RE

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 Suitable for IEEE Standard 896 Applications[†] 	SN75ALS056 DW OR N PACKAGE (TOP VIEW)
 SN75ALS056 is an Octal Transceiver 	A1 [1 20] B1
 SN75ALS057 is a Quad Transceiver 	A2 2 19 B2
 High-Speed Advanced Low-Power Schottky (ALS) Circuitry 	A3 [3 ₁₈] B3 A4 [4 17] B4
 Low Power Dissipation: 52.5 mW/Channel Max 	V _{CC} [5 16] GND A5 [6 15] B5
High-Impedance pnp Inputs	A6 [] 7 14]] B6 A7 [] 8 13]] B7
 Logic-Level 1-V Bus Swing Reduces Power Consumption 	A7 [° 13] B7 A8 [9 12] B8 CS [10 11] T/R
 Trapezoidal Bus Output Waveform Reduces Noise Coupling to Adjacent Lines 	
 Power-Up/Power-Down Protection (Glitch Free) 	SN75ALS057 DW OR N PACKAGE (TOP VIEW)
 Open-Collector Driver Outputs Allow Wired-OR Connections 	D1 [1 20] B1 R1 [2 19] E1
 Designed to Be a Faster, Lower-Power Functional Equivalent of National DS3896, 	D2 [3 18] B2 R2 [4 17] E2
DS3897	V _{CC} [] 5 16 [] GND D3 [] 6 15 [] B3
description	R3 🛛 7 14 🗋 E3
	D4 🛛 8 13 🗍 B4

The SN75ALS056 is an eight-channel, monolithic, high-speed, advanced low-power Schottky (ALS) device designed for two-way data communication in a densely populated backplane. The SN75ALS057 is a four-channel version with independent driver-input (Dn) and receiver-output (Rn) pins and a separate driver disable for each driver (En).

These transceivers feature open-collector driver outputs with series Schottky diodes to reduce capacitive loading to the bus. By using a 2-V pullup termination on the bus, the output signal swing is approximately 1 V, which reduces the power necessary to drive the bus load capacitance. The driver outputs generate trapezoidal waveforms that reduce crosstalk between channels. The drivers are capable of driving an equivalent dc load as low as 18.5 Ω . The receivers have internal low-pass filters to further improve noise immunity.

The SN75ALS056 and SN75ALS057 are characterized for operation from 0°C to 70°C.



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

[†] The transceivers are suitable for IEEE Standard 896 applications to the extent of the operating conditions and characteristics specified in this data sheet.

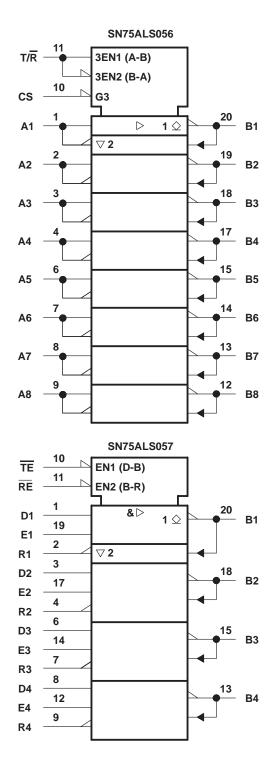
PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



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logic symbol[†]

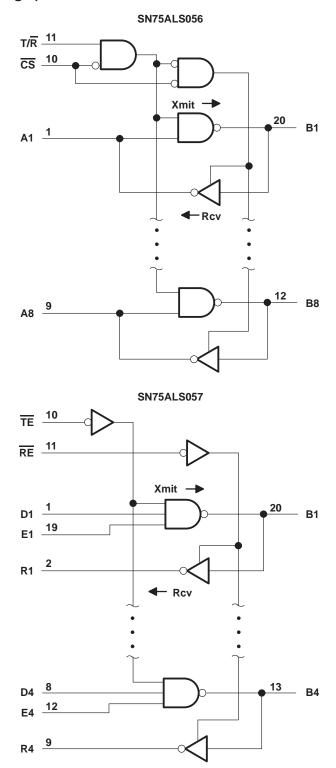


[†] These symbols are in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.



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logic diagram (positive logic)



[†] These symbols are in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.



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Function Tables

SN75ALS056 TRANSMIT/RECEIVE

CONT	ROLS	CHAN	NELS
CS	T/R	A ←	→ B
L	Н	T(A	B)
L	L	R(B	A)
н	Х	C)

SN75ALS057 TRANSMIT/RECEIVE

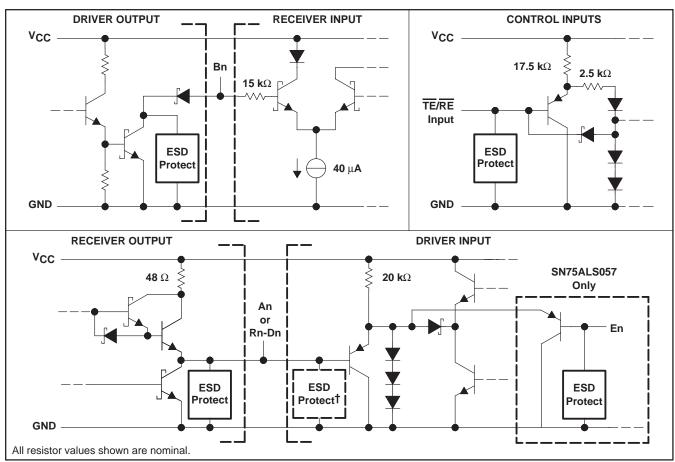
C	ONTROL	S		CHAN	INELS	
TE	RE	En	D	В	В	R
L	L	L	0)	F	२
L	L	Н	1	Г	F	र
L	Н	L)	[)
L	Н	Н	ר	Г	[)
н	L	Х)	F	र
Н	Н	Х)	[)

H = high level, L = low level, R = receive, T = transmit, D = disable, X = irrelevant

Direction of data transmission is from An to Bn for the SN75ALS056 and from Dn to Bn for the SN75ALS057. Direction of data reception is from Bn to An for the SN75ALS056 and from Bn to Rn for the SN75ALS057. Data transfer is inverting in both directions.



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schematics of inputs and outputs

[†] Additional ESD protection is on the SN75ALS057, which has separate receiver-output and driver-input pins.

absolute maximum ratings over operating free-air temperature (unless otherwise noted)[‡]

Supply voltage, V _{CC} (see Note 1)
Control input voltage, V ₁ 5.5 V
Driver input voltage, V ₁ 5.5 V
Driver output voltage, V _O 2.5 V
Receiver input voltage, V ₁ 2.5 V
Receiver output voltage, V _O 5.5 V
Continuous total power dissipation Table Continuous total power dissipation Rating Table
Storage temperature range, T _{stg}
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds: DW or N package
[‡] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and
functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not

implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: Voltage values are with respect to network ground terminal.



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DISSIPATION RATING TABLE										
PACKAGE	$T_A \le 25^{\circ}C$ POWER RATING	DERATING FACTOR ABOVE T _A = 25°C	T _A = 70°C POWER RATING	T _A = 125°C POWER RATING						
DW	1025 mW	8.2 mW/°C	656 mW	_						
N	1150 mW	9.2 mW/°C	736 mW	—						

recommended operating conditions

	MIN	NOM	MAX	UNIT
Supply voltage, V _{CC}	4.75	5	5.25	V
High-level driver and control input voltage, VIH	2			V
Low-level driver and control input voltage, VIL			0.8	V
Bus termination voltage	1.9		2.1	V
Operating free-air temperature, T _A	0		70	°C

electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

	PARAMETER		TEAT CONDITIONAT	SN	75ALS0	56	
	PARAMETER		TEST CONDITIONS [†] MIN TYP [†]		-1.5 1.69 0.5 1.2 40 100 -400	MAX	UNIT
VIK	Input clamp voltage at An,	T/R, or CS	II = -18 mA			-1.5	V
VIT	Receiver input threshold voltage at Bn			1.405		1.69	V
VOH			Bn at 1.2 V, CS at 0.8 V, T/ R at 0.8V, I _{OH} = – 400 μA	2.4			V
		An	Bn at 2 V , CS at 0.8 V, T/ R at 0.8 V, I _{OL} = 16 mA			0.5	
VOL	Low-level output voltage	Bn	An at 2 V, \overline{CS} at 0.8 V, T/ \overline{R} at 2 V, V _L = 2 V, R _L =18.5 Ω, See Figure 1	0.75		1.2 V	
		An, T/ \overline{R} or \overline{CS}	VI = VCC			40	
ЧΗ	High-level input current	Bn	V _I = 2 V, V _{CC} <u>=</u> 0 or 5.25 V, An at 0.8 V, T/R at 0.8 V			100	μA
١ _{IL}	Low level input current at	An, T/R, or CS	$V_I = 0.4 V$			-400	μA
IOS	Short-circuit output current at An		An at 0, Bn at 1.2 V, CS at 0.8 V, T/R at 0.8 V	-40		-120	mA
ICC	Supply current					75	mA
C _{O(B)}	Driver output capacitance				4.5		pF

[†] Typical values are at V_{CC} = 5 V, T_A = 25° C.



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electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

	PARAMETER		TEST CONDITIONS	SN	75ALS0	57	UNIT
	PARAMETER		TEST CONDITIONS	MIN	TYP [†]	MAX	UNIT
VIK	Input clamp voltage at Dn, En, TE, or RE		I _I = -18 mA			-1.5	V
VIT	Receiver input threshold voltage	at Bn		1.41		1.69	V
VOH	High-level output voltage at Rn		Bn at 1.2 V, RE at 0.8 V, I _{OH} = -400 μA	2.4			V
		Rn	Bn at 2 V, RE at 0.8 V, I _{OL} = 16 mA			0.5	
V _{OL}	V _{OL} Low-level output voltage	Bn	Dn at 2 V, En at 2 V, TE at 0.8 V, V _L = 2 V, R _L = 18.5 Ω, See Figure 1	0.75		1.2	V
		<u>Dn</u> , En <u>,</u> TE, or RE	VI = VCC			40	
ΙΗ	High-level input current	Bn	V _I = 2 V, V _{CC} = 0 or 5.25 V, <u>Dn</u> at 0.8 V, En at 0.8 V, TE at 0.8 V			100	μA
۱ _{IL}	Low-level input current at Dn, Er	, TE, or RE	$V_I = 0.4 V$			-400	μA
IOS	Short-circuit output current at Rn		<u>Rn</u> at 0, Bn at 1.2 V, RE at 0.8 V	-40		-120	mA
ICC	Supply current					40	mA
C _{O(B)}	Driver output capacitance				4.5		pF

[†]Typical values are at $V_{CC} = 5 V$, $T_A = 25^{\circ}C$.

switching characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

	PARAMETER		TO	TEST CONDITIONS	SN75ALS056 DRIVER			UNIT		
		(INPUT)	(OUTPUT)		MIN	түр†	MAX			
^t PLH1	Propagation delay time, low-to-high-level output		Bn	An and T/\overline{R} at 2 V, V _L = 2 V, B: 1 = 18 O C = -30 pF			24	20		
^t PHL1	Propagation delay time, high-to-low-level output	03	DI	$R_L 1 = 18 \Omega_r$, $C_L = 30 pF$, $R_L 2$ not connected, See Figure 2			20	ns		
^t PLH2	Propagation delay time, low-to-high-level output	4.5	Bn	\overline{CS} at 0.8 V, T/ \overline{R} at 2 V, V _L = 2 V, R _L 1 = 18 Ω,			19	20		
^t PHL2	Propagation delay time high-to-low-level output	An		DII	R_L2 not connected, $C_L = 30 pF$, See Figure 2,			18	ns	
^t PLH3	Propagation delay time, low-to-high-level output			Bn	$V_{I(An)} = 5 V, CS at 0.8 V,$ $R_{L}1 = 18 \Omega, C_{L} = 30 pF,$ $R_{L}2 = 30 PF,$			25	20	
^t PHL3	Propagation delay time, high-to-low-level output	T/R	BU		ווס	R_L2 not connected, $V_L = 2 V$, See Figure 3,			35	ns
^t TLH	Transition time, low-to-high-level output	An	Bn	CS at 0.8 V, T/R at 2 V, VL = 2 V, CL = 30 pF,	1	3	11	ns		
^t THL	Transition time, high-to-low-level output		BU	Bn		$R_L 1 = 18 \Omega$, $R_L 2$ not connected, See Figure 2	1	3	6	115

† Typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$



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switching characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

	PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS	SN75A RECE		UNIT
			(001201)		MIN MAX		
^t PLH4	Propagation delay time, low-to-high-level output	Bn	An	$\overline{\text{CS}}$ at 0.8 V, T/ $\overline{\text{R}}$ at 0.8 V, R _L 1 = 390 Ω,		18	ns
^t PHL4	Propagation delay time, high-to-low-level output	Ы	АП	$R_L 2 = 1.6 \text{ k}\Omega$, $C_L = 30 \text{ pF}$, See Figure 4		18	115
^t PLZ1	Output disable time from low level	T/R	An	$\overline{\text{CS}}$ at 0.8 V, V _{I(Bn)} = 2 V, V _L = 5 V, R _L 1 = 390 Ω , R _L 2 not connected, C _L = 15 pF, See Figure 3		20	ns
^t PZL1	Output enable time to low level	T/R	An	$\label{eq:cs} \begin{array}{l} \overline{\text{CS}} \text{ at } 0.8 \ \text{V}, \ \text{V}_{I(Bn)} = 2 \ \text{V}, \ \text{V}_{L} = 5 \ \text{V}, \\ \text{R}_{L}1 = 390 \ \Omega, \ \text{R}_{L}2 = 1.6 \ \text{k}\Omega, \\ \text{C}_{L} = 30 \ \text{pF}, \ \text{See Figure } 3 \end{array}$		40	ns
^t PHZ1	Output disable time from high level	T/R	An	$\overline{\text{CS}}$ at 0.8 V, V _{I(Bn)} = 0, V _L = 0, R _L 1 = 390 Ω , R _L 2 not connected, C _L = 15 pF, See Figure 3		17	ns
^t PZH1	Output enable time to high level	T/R	An	$\overline{\text{CS}}$ at 0.8 V, VI _{(Bn}) = 0, V _L = 0, R _L 1 not connected, R _L 2 = 1.6 kΩ, C _L = 30 pF, See Figure 3		15	ns
^t PLZ2	Output disable time from low level	CS	An	Bn at 2 V, T/ \overline{R} at 0.8 V, C _L = 5 pF, V _L = 5 V, R _L 1 = 390 Ω , R _L 2 not connected, See Figure 5		18	ns
^t PZL2	Output enable time to low level	CS	An	Bn at 2 V, T/ \overline{R} at 0.8 V, C _L = 30 pF, V _L = 5 V, R _L 1 = 390 Ω , R _L 2 = 1.6 k Ω , See Figure 5		15	ns
^t PHZ2	Output disable time from high level	CS	An	Bn at 0.8 V, T/ \overline{R} at 0.8 V, C _L = 5 pF, V _L = 0, R _L 1 = 390 Ω, R _L 2 not connected, See Figure 5		8	ns
^t PZH2	Output enable time to high level	CS	An	Bn at 0.8 V, T/ \overline{R} at 0.8 V, C _L = 30 pF, V _L = 0, R _L 1 not connected, R _L 2 = 1.6 k Ω , See Figure 5		17	ns
^t w(NR)	Receiver noise rejection pulse duration	Bn	An	\overline{CS} at 0.8 V, T/R at 0.8 V, RL1 = 390 Ω, RL2 = 1.6 kΩ, CL = 30 pF, VL = 5 V, See Figure 6	3		ns



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switching characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

	PARAMETER		PARAMETER FROM TO TEST CONDI		TEST CONDITIONS					UNIT	
			(001P01)		MIN	TYP [†]	MAX				
^t PLH1	Propagation delay time, low-to-high-level output	TE	Pn	Dn, En, \overline{RE} at 2 V, V _L = 2 V,			24	20			
^t PHL1	Propagation delay time, high-to-low-level output		Bn		RL2 not connected, RL1 = 18 Ω, See Figure 2, CL = 30 pF			20	ns		
^t PLH2	Propagation delay time, low-to-high-level output	Dn or En		Bn	$\overline{\text{TE}}$ at 0.8 V, $\overline{\text{RE}}$ at 2 V, V ₁ = 2 V, R ₁ 1 = 18 Ω,			19			
^t PHL2	Propagation delay time, high-to-low-level output		DII	R_L^2 not connected, $C_L = 30 \text{ pF}$, See Figure 2			18	ns			
^t TLH	Transition time, low-to-high-level output				Description	Do	RE at 2 V, V _L = 2 V, TE at 0.8 V, R _L 1 = 18 Ω,,	1	3	11	
^t THL	Transition time, high-to-low-level output	UNUTEN	on or En Bn	R_L^2 not connected, $C_L = 30 \text{ pF}$, See Figure 2	1	3	6	ns			

[†] Typical values are at $V_{CC} = 5 V$, $T_A = 25^{\circ}C$.

switching characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (continued)

PARAMETER		FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS	SN75AI RECE		UNIT
					MIN	MAX	
^t PLH4	Propagation delay time, low-to-high-level output	Bn	Rn	$\overline{\text{RE}}$ at 0.8 V, $\overline{\text{TE}}$ at 2 V, V _L = 5 V,		18	ns
^t PHL4	Propagation delay time, high-to-low-level output	Ы	KII	$R_L 1 = 390 \Omega$, $R_L 2 = 1.6 k\Omega$, $C_L = 30 pF$, See Figure 4		18	115
^t PLZ2	Output disable time from low level	RE	Rn	Bn at 2 V, $\overline{\text{TE}}$ at 2 V, V _L = 5 V, C _L = 5 pF, R _L 1 = 390 Ω , R _L 2 not connected, See Figure 5		18	ns
^t PZL2	Output enable time to low level	RE	Rn	Bn at 2 V, $\overline{\text{TE}}$ at 2 V, V _L = 5 V, C _L = 30 pF, R _L 1 = 390 Ω, R _L 2 = 1.6 kΩ, See Figure 5		15	ns
^t PHZ2	Output disable time from high level	RE	Rn	Bn at 0.8 V, $\overline{\text{TE}}$ at 2 V, VL = 0, CL = 5 pF, RL1 = 390 Ω , RL2 not connected, See Figure 5		17	ns
^t PZH2	Output enable time to high level	RE	Rn	Bn at 0.8 V, $\overline{\text{TE}}$ at 2 V, VL = 0, CL = 30 pF, RL1 not connected, RL2 = 1.6 k Ω , See Figure 5		17	ns
^t w(NR)	Receiver noise rejection pulse duration	Bn	Rn	TE at 2 V, RE at 0.8 V, V _L = 0, R _L 1 = 390 Ω , R _L 2 = 1.6 k Ω , C _L = 30 pF, See Figure 6	3		ns



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switching characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (continued)

PARAMETER		FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS	SN75ALS057 DRIVER PLUS RECEIVER		UNIT
					MIN	MAX	
^t PLH6	Propagation delay time, low-to-high-level output	Dn	Rn	$\overline{\text{RE}}$ at 0.8 V, $\overline{\text{TE}}$ at 0.8 V, R_{L} 1 = 390 Ω , R_{L} 2 = 1.6 k Ω , C_{L} = 30 pF, See Figure 7		40	ns
^t PHL6	Propagation delay time, high-to-low-level output					40	

PARAMETER MEASUREMENT INFORMATION

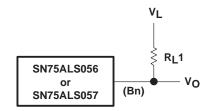
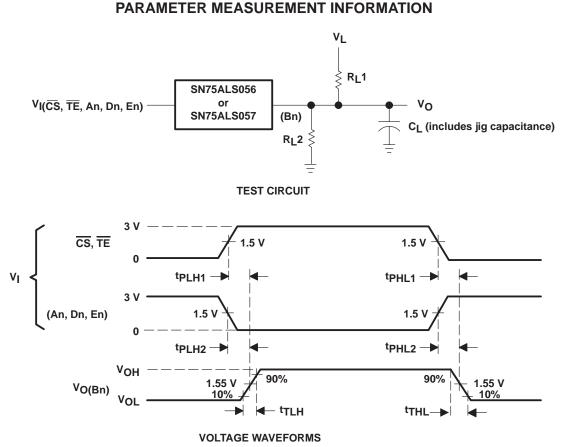


Figure 1. Driver Low-Level-Output-Voltage Test Circuit



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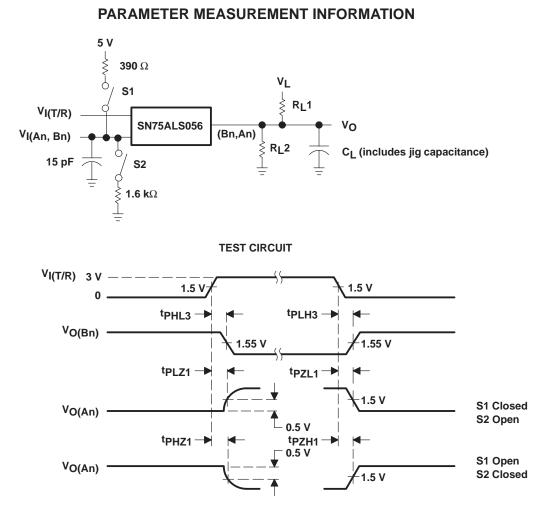


NOTE A: $t_f = t_f \le 5$ ns from 10% to 90%





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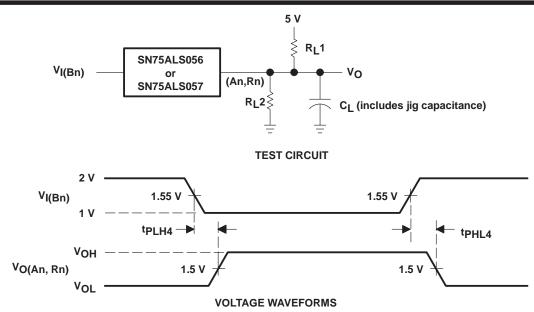
VOLTAGE WAVEFORMS

NOTE A: $t_r = t_f \le 5$ ns from 10% to 90%

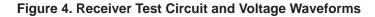
Figure 3. Propagation Delay From T/R to An or Bn Test Circuit and Voltage Waveforms

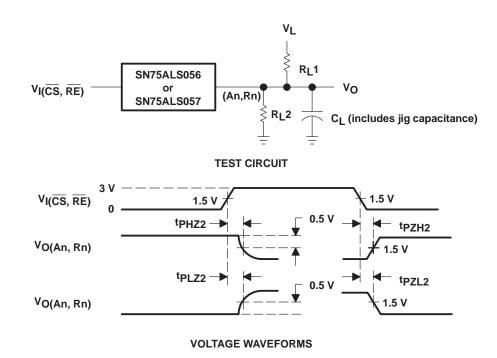


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NOTE A: $t_r = t_f \le 5$ ns from 10% to 90%



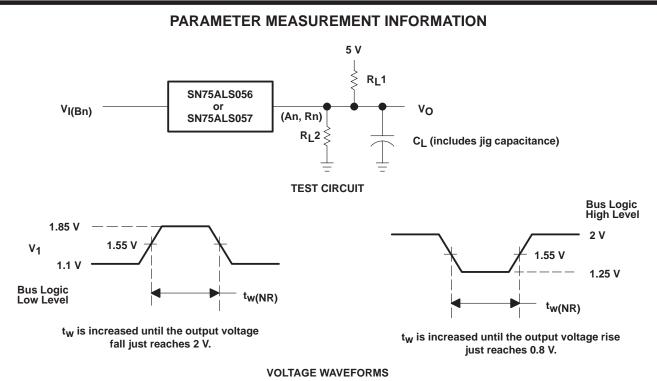


NOTE A: $t_{f} = t_{f} \le 5$ ns from 10% to 90%



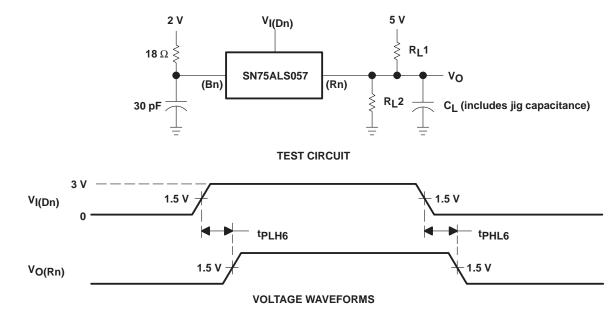


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NOTE A: $t_r = t_f \le 5$ ns from 10% to 90%





NOTE A: $t_{f} = t_{f} \le 5$ ns from 10% to 90%





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